

September 2000

FQD7P06 / FQU7P06

60V P-Channel MOSFET

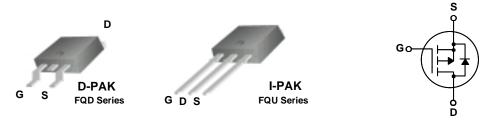
General Description

These P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as automotive, DC/ DC converters, and high efficiency switching for power management in portable and battery operated products.

Features

- -5.4A, -60V, $R_{DS(on)}$ = 0.45 Ω @V_{GS} = -10 V Low gate charge (typical 6.3 nC)
- Low Crss (typical 25 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability



Absolute Maximum Ratings $T_C = 25$ °C unless otherwise noted

Symbol	Parameter		FQD7P06 / FQU7P06	Units
V _{DSS}	Drain-Source Voltage		-60	V
I _D	Drain Current - Continuous (T _C = 25°C)		-5.4	А
	- Continuous (T _C = 100°C))	-3.42	А
I _{DM}	Drain Current - Pulsed	(Note 1)	-21.6	А
V _{GSS}	Gate-Source Voltage		± 25	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	90	mJ
I _{AR}	Avalanche Current	(Note 1)	-5.4	Α
E _{AR}	Repetitive Avalanche Energy	(Note 1)	2.8	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	-7.0	V/ns
P_{D}	Power Dissipation (T _A = 25°C) *		2.5	W
	Power Dissipation (T _C = 25°C)		28	W
	- Derate above 25°C		0.22	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		4.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		50	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		110	°C/W

Symbol	Parameter	Test Conditions	;	Min	Тур	Max	Units
Off Cha	aracteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$		-60			V
ΔBV _{DSS} / ΔΤ _J	Breakdown Voltage Temperature Coefficient	I _D = -250 μA, Reference	to 25°C		-0.07		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -60 V, V _{GS} = 0 V				-1	μΑ
		$V_{DS} = -48 \text{ V}, T_{C} = 125 ^{\circ}\text{C}$				-10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = -25 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = 25 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
On Cha	racteristics						
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$		-3.0		-5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = -10 \text{ V}, I_D = -2.7 \text{ A}$			0.36	0.451	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = -30 \text{ V}, I_{D} = -2.7 \text{ A}$	(Note 4)		3.8		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			225 110 25	295 145 32	pF pF
	ing Characteristics				25	32	рг
t _{d(on)}	Turn-On Delay Time	$V_{DD} = -30 \text{ V}, I_{D} = -7.0 \text{ A},$ $R_{G} = 25 \Omega$			7	25	ns
t _r	Turn-On Rise Time				50	110	ns
t _{d(off)}	Turn-Off Delay Time				7.5	25	ns
t _f	Turn-Off Fall Time		(Note 4, 5)	-	25	60	ns
Q _g	Total Gate Charge	$V_{DS} = -48 \text{ V}, I_{D} = -7.0 \text{ A},$		-	6.3	8.2	nC
Q _{gs}	Gate-Source Charge	V _{GS} = -10 V			1.6		nC
Q _{gd}	Gate-Drain Charge	(Note 4			3.1		nC
Drain-S	Source Diode Characteristics ar Maximum Continuous Drain-Source Dio		S			-5.4	А
I _{SM}	Maximum Pulsed Drain-Source Diode F			1		-21.6	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -5.4 \text{ A}$				-4.0	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_S = -7.0 \text{ A,}$ $dI_F / dt = 100 \text{ A/}\mu\text{s}$ (Note 4)			77		ns
Q _{rr}							

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 3.6mH, I_{AS} = -5.4A, V_{DD} = -25V, R_G = 25 Ω, Starting T_J = 25°C 3. I_{SD} \leq -7.0A, di/dt \leq 300A/μs, V_{DD} \leq BV_{DSS}, Starting T_J = 25°C 4. Pulse Test : Pulse width \leq 300μs, Duty cycle \leq 2% 5. Essentially independent of operating temperature

Typical Characteristics

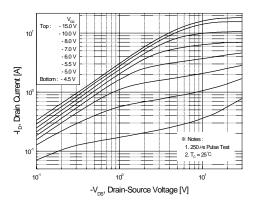


Figure 1. On-Region Characteristics

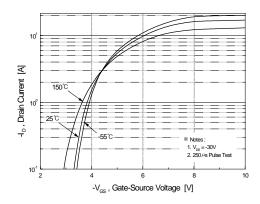


Figure 2. Transfer Characteristics

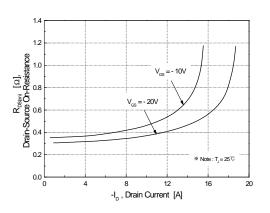


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

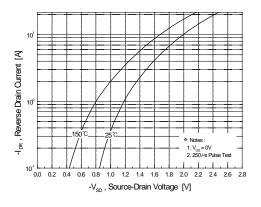


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

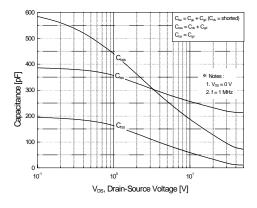


Figure 5. Capacitance Characteristics

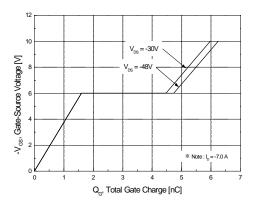
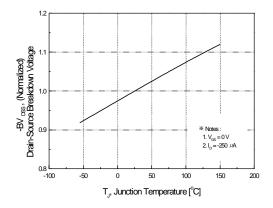


Figure 6. Gate Charge Characteristics

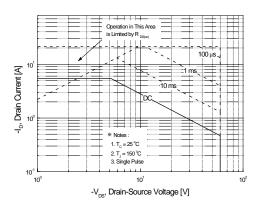




2.5 (Notices) 1.5 (Notices) 1.

Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



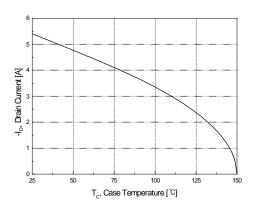


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

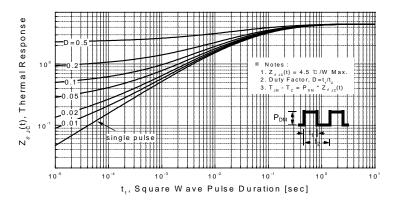
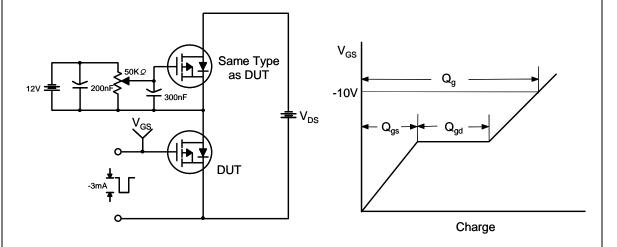


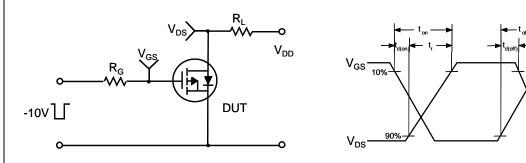
Figure 11. Transient Thermal Response Curve

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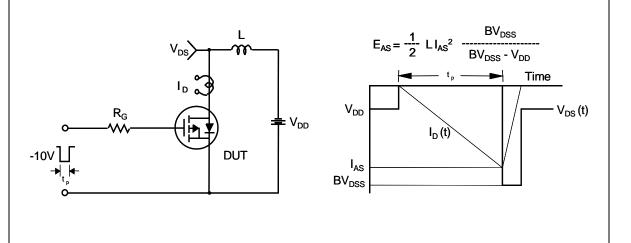
Gate Charge Test Circuit & Waveform



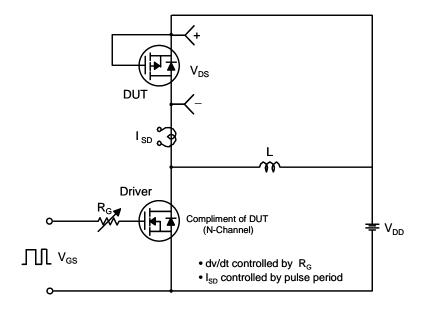
Resistive Switching Test Circuit & Waveforms

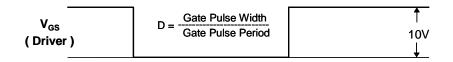


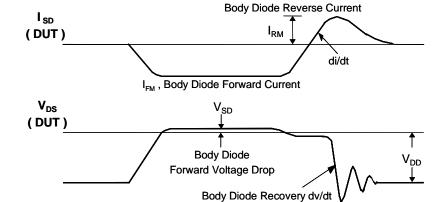
Unclamped Inductive Switching Test Circuit & Waveforms

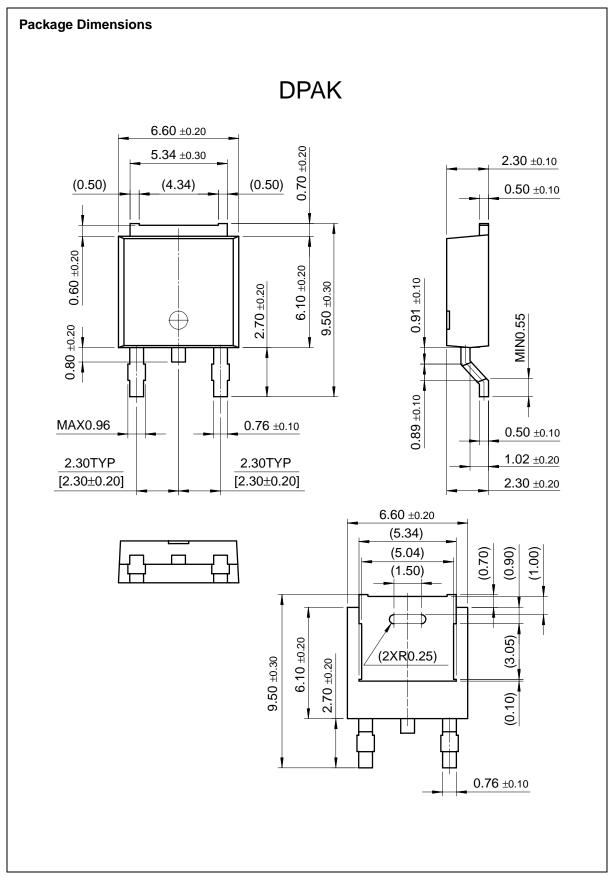


Peak Diode Recovery dv/dt Test Circuit & Waveforms



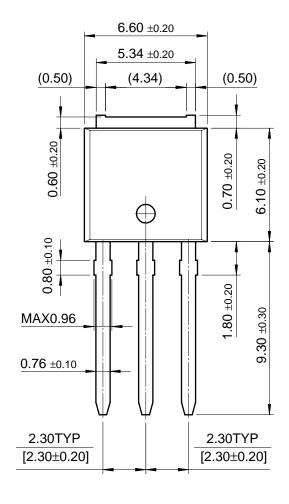


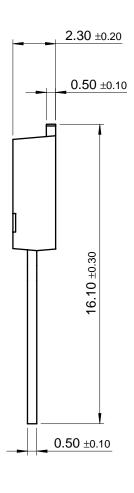






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